

<b>Notice of References Cited</b>	Application/Control No. 10/792,175		Applicant(s)/Patent Under Reexamination FINKE-ANLAUFF ET AL.	
	Examiner Kiran K. Shrestha		Art Unit 2109	Page 1 of 1

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*	B	US-2002/0054157	05-2002	Hayashi et al.	345/838
*	C	US-2002/0113803	08-2002	Samra et al.	345/619
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	WO 02/057959 A2	07-2002	WO	Rothmüller et al.	
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**NON-PATENT DOCUMENTS**

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